



# VLSI Testing

## 積體電路測試

***Logic Built-In Self Test (BIST)***  
***Part 2: ORA, BIST Architecture\****

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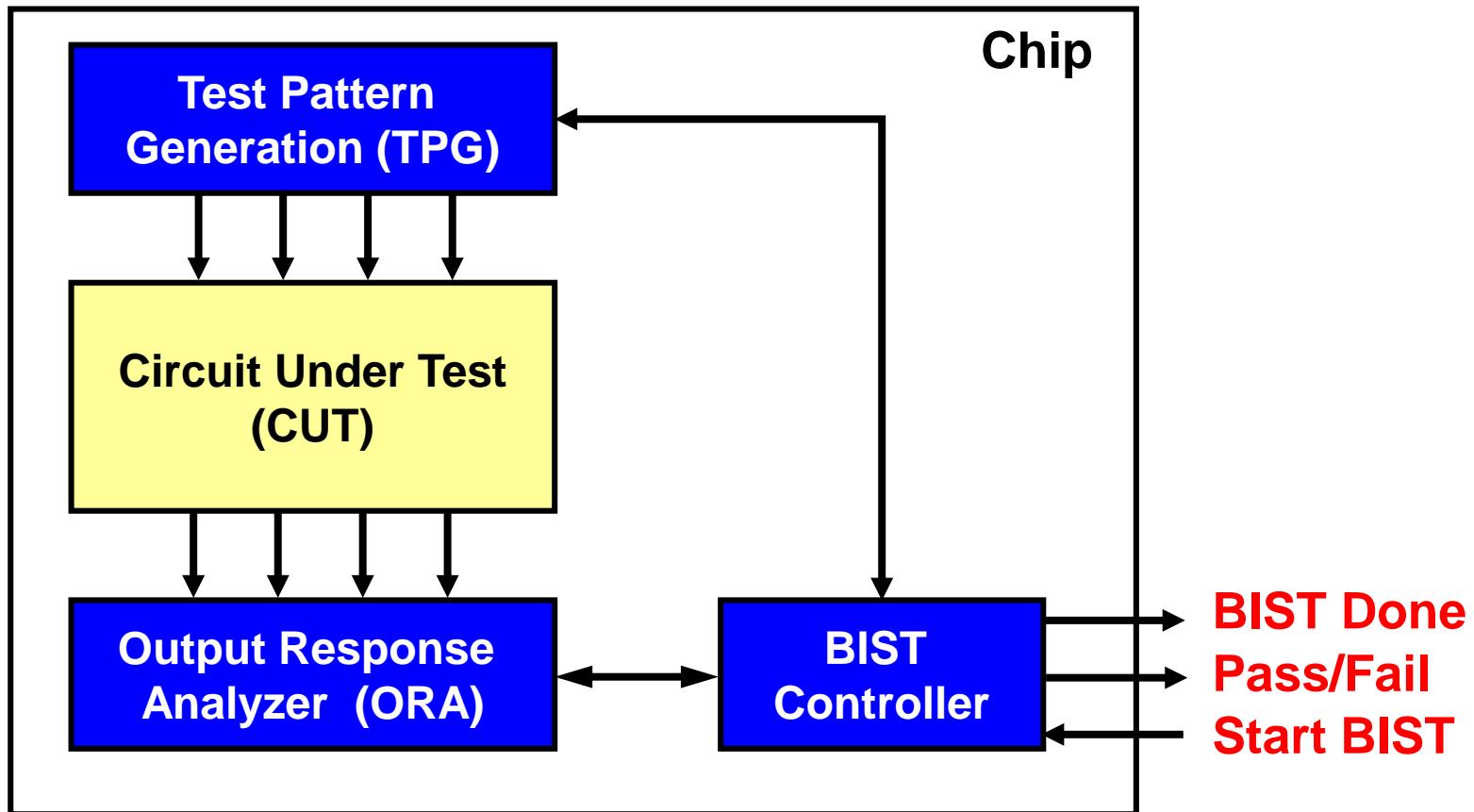
**Lab. of Dependable Systems**

**Graduate Institute of Electronics Engineering**  
**National Taiwan University**

\* Some pictures are courtesy of Prof. Shi-yu Huang, NTHU

# Architecture of BIST (Review)

- Three components: **BIST Controller**, **TPG**, **ORA**
- Three I/O Pins: **Start BIST**, **BIST Done**, **Pass/Fail**



# Why Am I Learning This?

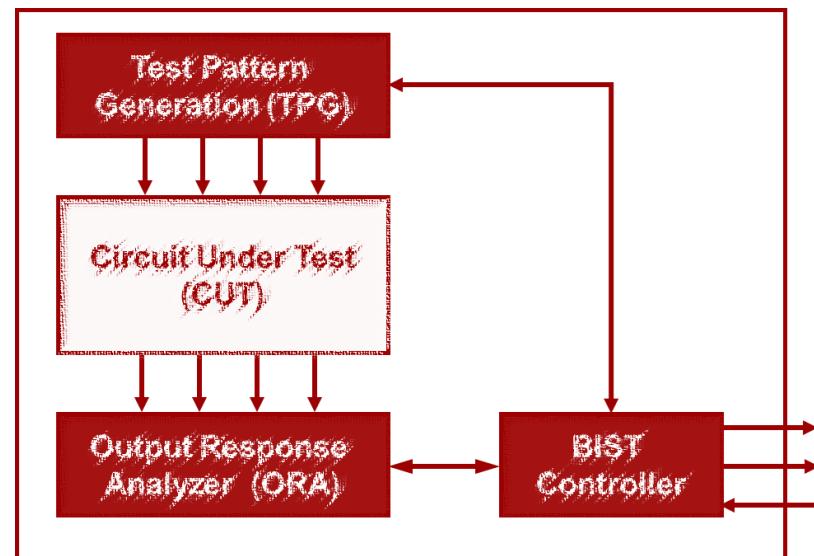
- Output Response Analyzer
  - ◆ Observe CUT output responses on chip
  - ◆ Very small area but correct Pass/Fail decision

***“What the superior man seeks is in himself;  
what the small man seeks is in others.”***

君子求諸己，小人求諸人  
**(Confucius)**

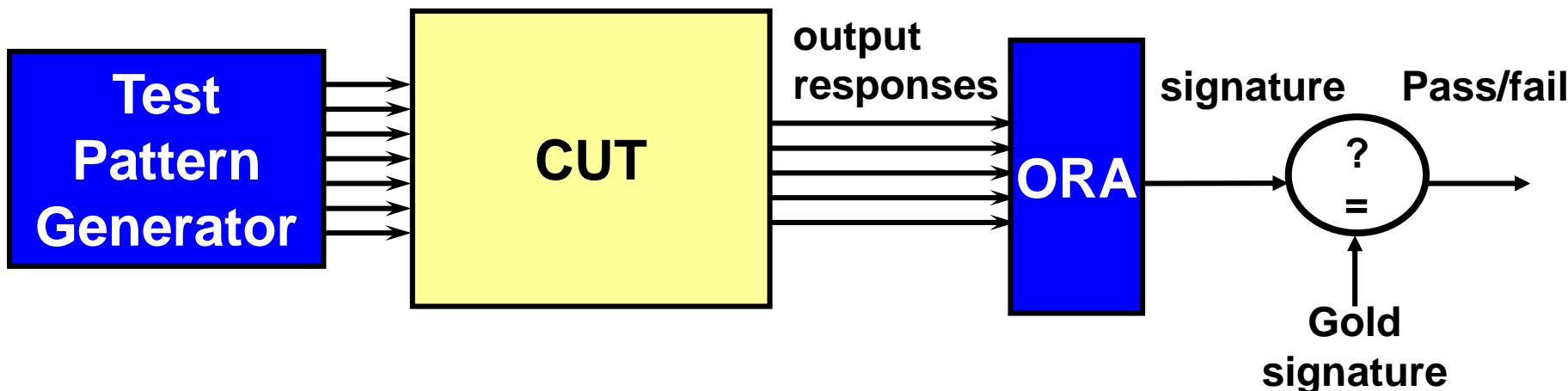
# BIST Part 2

- Part 1
  - ◆ Introduction
  - ◆ Test Pattern Generation
- Part 2
  - ◆ Output Response Analysis
  - ◆ BIST Architecture
  - ◆ Issues with BIST
  - ◆ Conclusions



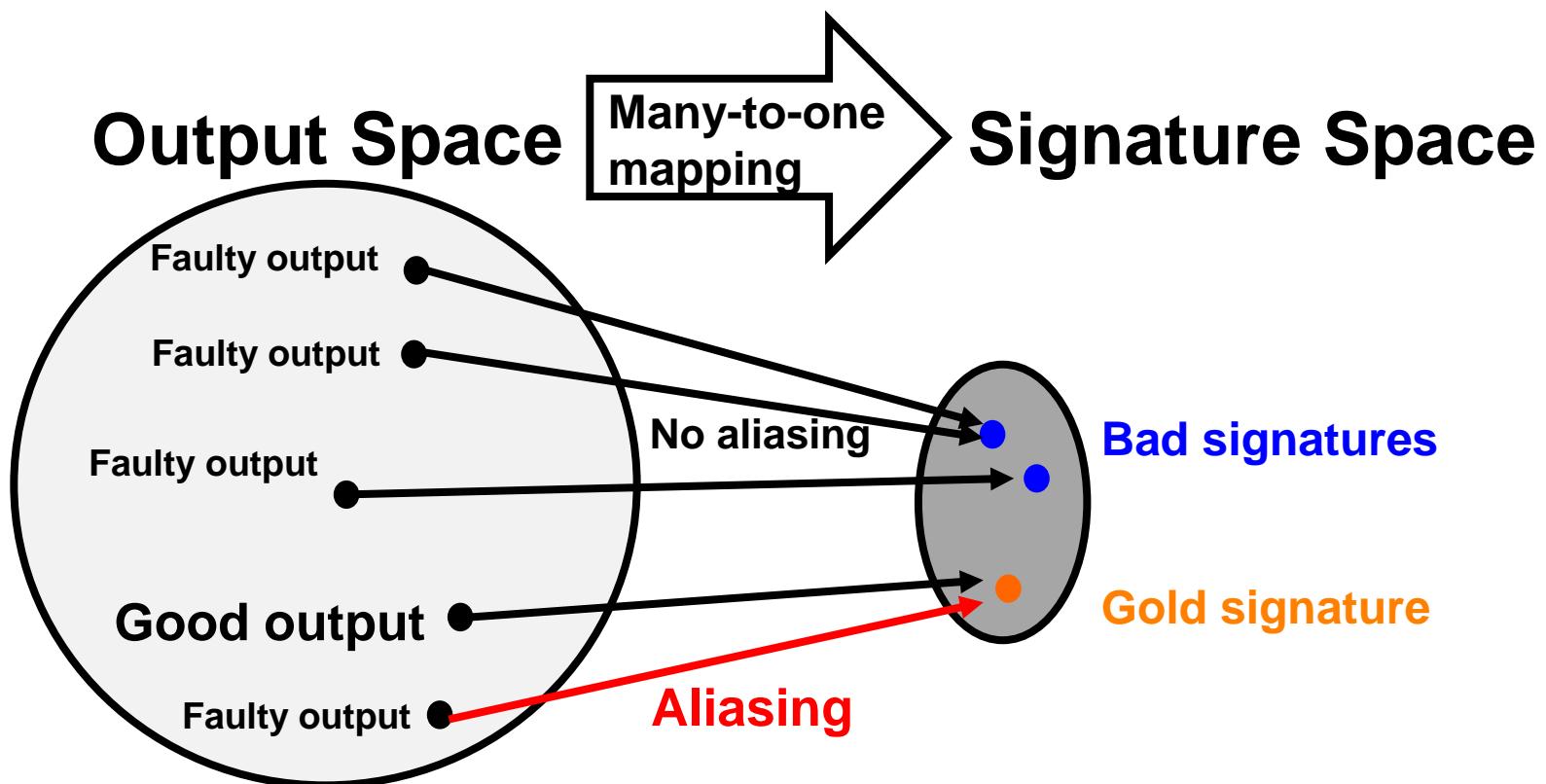
# Output Response Analyzer

- What is ORA?
  - ◆ Compress CUT output responses into a small *signature*
  - ◆ Compare signature with *gold signature* to determine pass or fail
  - ◆ ORA also called *signature analyzer*
- What is good ORA? (very difficult to meet all requirements)
  - ◆ 1. Signature as **small** as possible
  - ◆ 2. **Correct Pass/Fail decision** (*i.e.* **low aliasing**, see next slide)
  - ◆ 3. **Small area**
  - ◆ 4. **Diagnosis support**



# Aliasing

- **Aliasing** occurs when
  - ◆  $\text{signature}_{\text{faulty output}} = \text{signature}_{\text{good output}}$  (*gold signature*)
- Aliasing → Fault coverage loss → **Test escapes**
  - ◆ Defective circuits pass tests (*Very bad!*)



# Probability of Aliasing

- Aliasng depends on many factors:
  - ◆ CUT, faults, test pattern, ORA structure
  - ◆ Exact analysis of aliasng difficult
  - ◆ Just probability analysis is good enough
- *Probability of Aliasng (PAL)*

$$PAL = \frac{\text{number of faulty outputs that generate gold signature}}{\text{total number of faulty outputs}}$$

- ◆ PAL between 0 and 1. Lower is better.

Good ORA Requires Low PAL

# Quiz

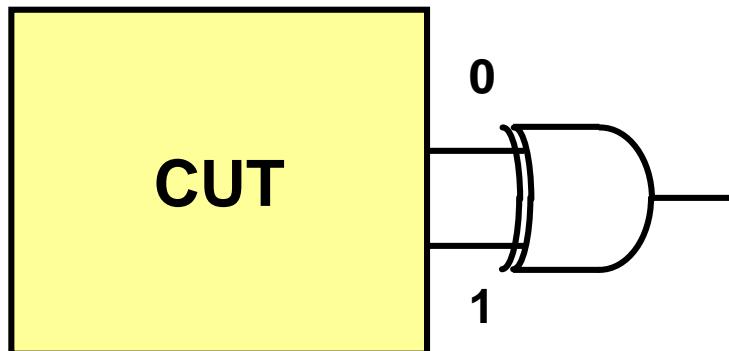
**Q1:** We use OR gate as ORA. Suppose good output is '01', what is gold signature?

**ANS:**

**Q2:** What is PAL of this ORA? Suppose '00, 01 10, 11' equally likely

$$PAL = \frac{\text{number of faulty outputs that generate gold signature}}{\text{total number of faulty outputs}}$$

**ANS:**



# BIST Part 2

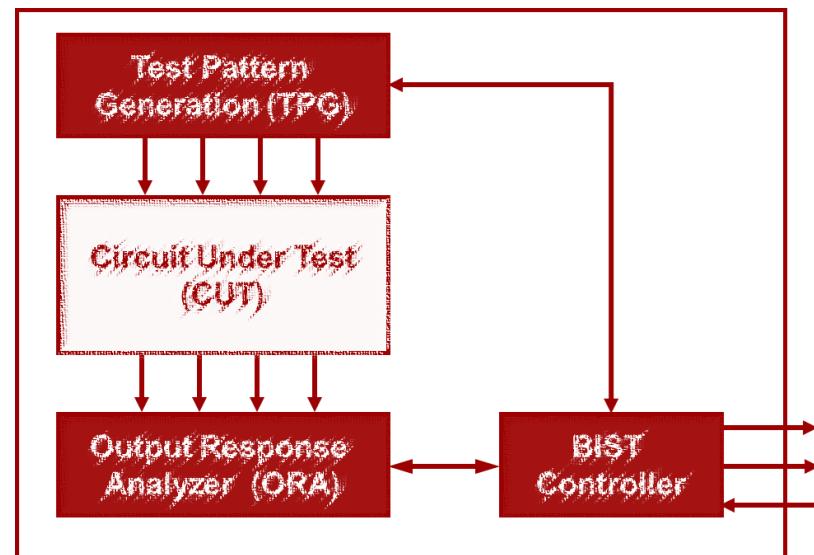
- **Output Response Analysis**

- ◆ **Simple ORA**

- \* **Duplication, Reverse operation**
    - \* **Checksum (aka. Parity Checker)**
    - \* **Ones counter**
    - \* **Transition counter**

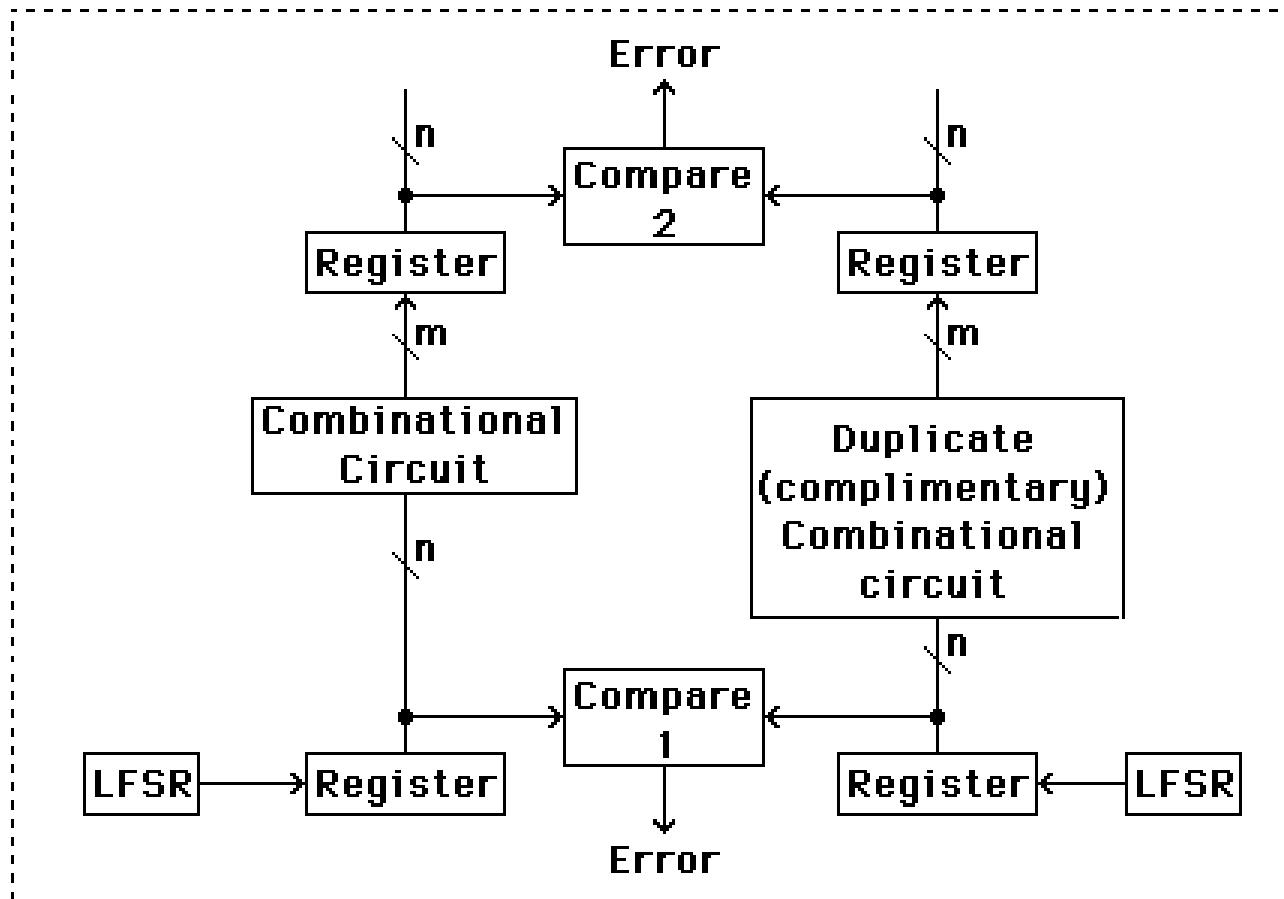
- ◆ LFSR-based

- BIST Architecture
- Issues with BIST
- Conclusions



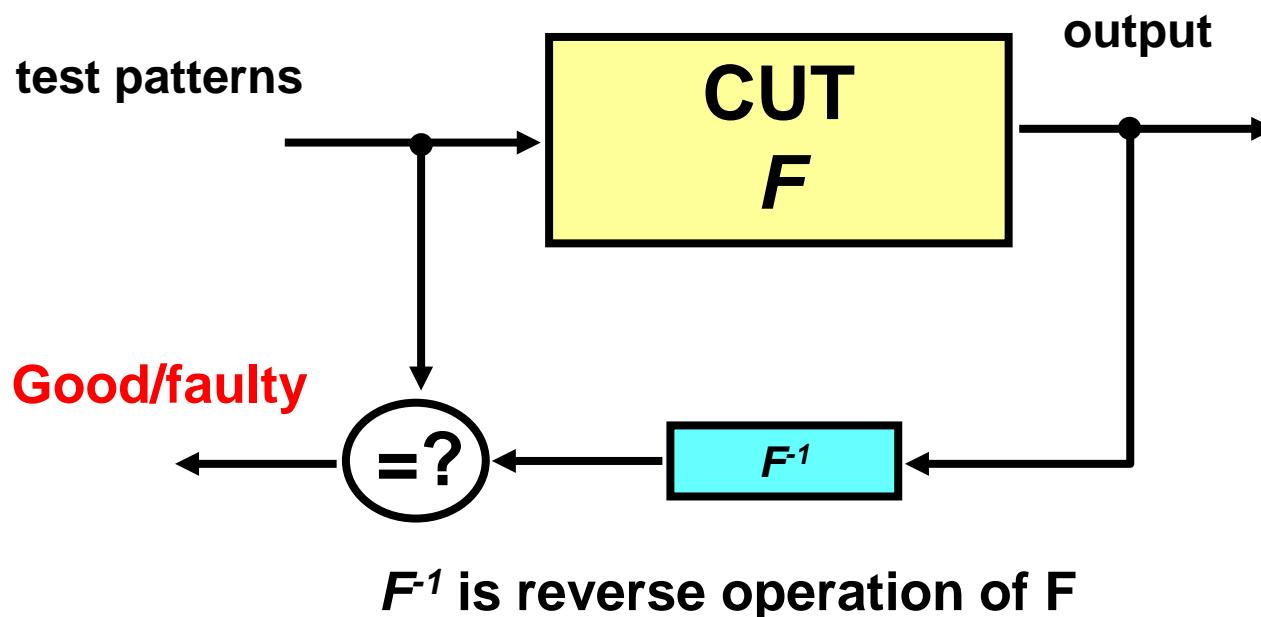
# Duplication

- Advantage: low aliasing; good for on-line BIST
- Disadvantages: too big in area



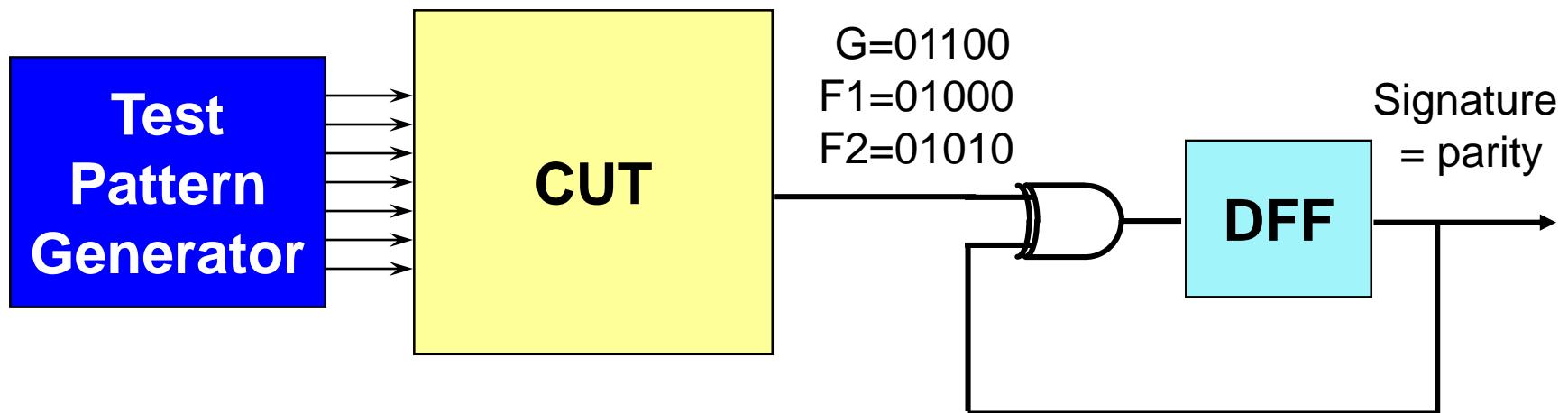
# Reverse Operation

- Advantages
  - ◆ Applicable to both on-line and off-line BIST
  - ◆ Low aliasing
- Disadvantages
  - ◆ Not generally applicable to all CUT



# Parity Checker

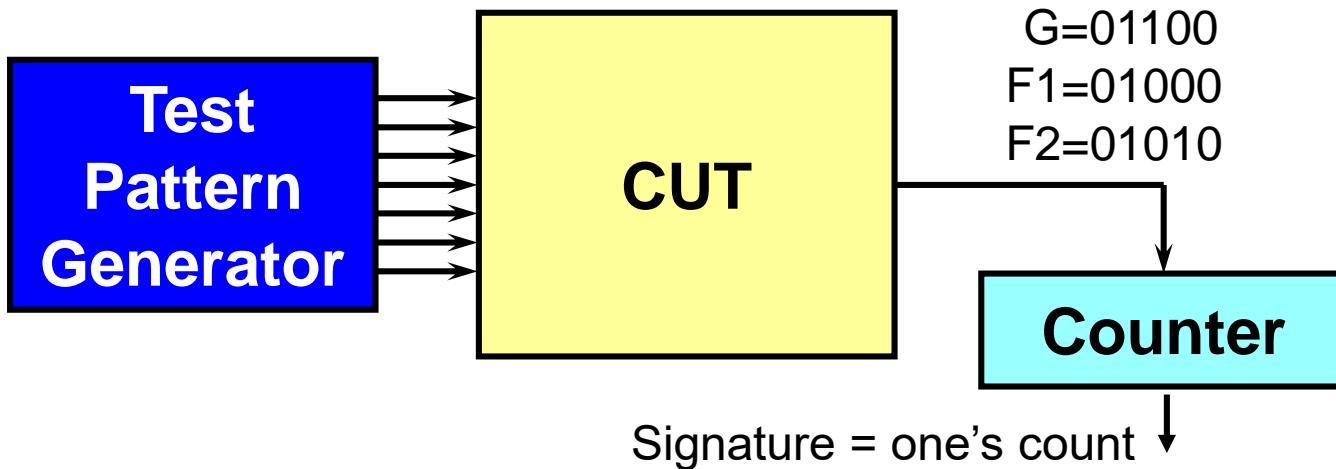
- Signature = Inversion parity of CUT output
  - ◆ Odd or even
- Example (initially DFF=0)
  - ◆ Good CUT output = 01100 → 0 gold signature
  - ◆ Faulty CUT1 output = 01000 → 1 detected, no aliasing
  - ◆ Faulty CUT2 output = 01010 → 0 not detected, aliasing



$$PAL = \frac{\text{number of faulty outputs that generate gold signature}}{\text{total number of faulty outputs}} = \frac{16 - 1}{2^5 - 1} = \frac{15}{31}$$

# Ones Counter

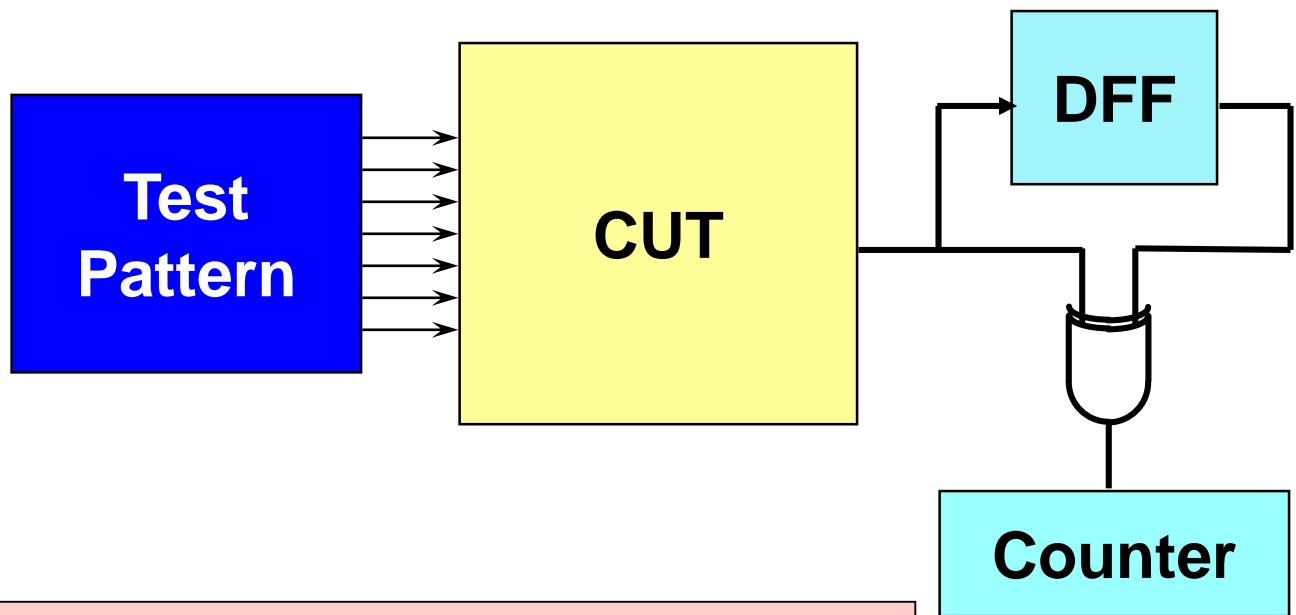
- Signature = number of ones
- Example: **sequence length=5=m; signature=2=n;**
  - ◆ Good CUT output = 01100 → 2 gold signature
  - ◆ Faulty CUT1 output = 01000 → 1 detected, no aliasing
  - ◆ Faulty CUT2 output = 01010 → 2 not detected, aliasing



$$PAL = \frac{C_n^m - 1}{2^m - 1} = \frac{C_2^5 - 1}{2^5 - 1} = \frac{10 - 1}{32 - 1} = \frac{9}{31}$$

# Transition Counter

- Signature = number of transitions ( $0 \rightarrow 1, 1 \rightarrow 0$ )
- Example: sequence length=5=m; signature=2=n;
  - ◆ Good CUT output = 01100 → 2
  - ◆ Faulty CUT1 output = 01000 → 2 not detected, aliasing
  - ◆ Faulty CUT2 output = 01010 → 4 detected, no aliasing



$$PAL = \frac{2C_n^{m-1} - 1}{2^m - 1} = \frac{2C_2^4 - 1}{2^5 - 1} = \frac{12 - 1}{32 - 1} = \frac{11}{31}$$

Signature  
= transition count

# Summary

- **Output Response Analyzer**
  - ◆ Compress CUT output responses into **signatures**
  - ◆ Aliasing mean **faulty outputs compressed into gold signature**
    - \* induces **test escape**
  - ◆ **Probability of aliasing (PAL)**

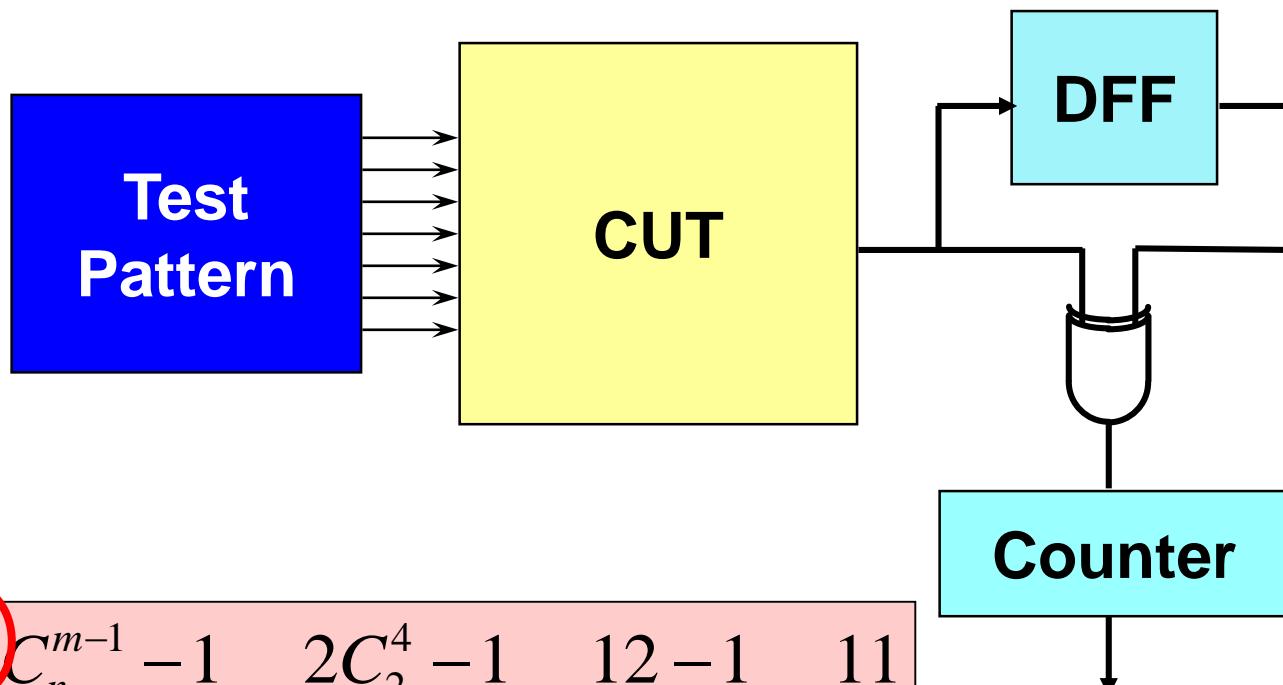
$$PAL = \frac{\text{number of faulty outputs that generate gold signature}}{\text{total number of faulty outputs}}$$

- ◆ **Simple ORA**
  - \* Duplication
  - \* Parity Checker
  - \* Ones counter
  - \* Transition counter

**These ORA not Good Enough**

# FFT: Transition Counter

- Q: Why factor of 2 in PAL?



$$PAL = \frac{2C_n^{m-1} - 1}{2^m - 1} = \frac{2C_2^4 - 1}{2^5 - 1} = \frac{12 - 1}{32 - 1} = \frac{11}{31}$$